FONDEUR ET AL

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## Amendments to the Claims

1. (currently amended) A photolithographic mask set
comprising:

a master mask including a first pattern having features for forming part of a planar <u>lightwave</u> circuit, the first pattern including a featureless region disposed therein such that the planar <u>lightwave</u> circuit is incomplete; and,

a slave mask including a second pattern having features for completing the planar lightwave circuit.

- 2. (original) A photolithographic mask set according to claim
- 1, wherein the second pattern is designed to correct systematic errors induced by the master mask.
- 3. (original) A photolithographic mask set according to claim
- 1, wherein the second pattern has been experimentally optimized using a plurality of other slave masks.
- 4. (original) A photolithographic mask set according to claim
- 1, wherein a perimeter of the featureless region and a perimeter of the slave mask have a same shape and dimensions.
- 5. (original) A photolithographic mask set according to claim
- 1, wherein the master mask and the slave mask are written on different regions of a same plate.
- 6. (original) A photolithographic mask set according to claim
- 5, wherein the slave mask is written at a periphery of the master mask.

FONDEUR ET AL

Serial No. 10/736,295

Filed: 12/15/2003

7. (original) A photolithographic mask set according to claim

1, wherein the master mask and the slave mask are written on different plates.

8. (original) A photolithographic mask set according to claim

7, comprising a plurality of other slave masks written on the

same plate as the slave mask.

9. (withdrawn - currently amended) A method of fabricating a planar circuit utilizing a photolithographic mask set, the

method comprising the steps of:

(a) providing a photolithographic mask set including a master mask and a slave mask, the master mask including a first pattern having features for forming part of the planar <a href="lightwave">lightwave</a> circuit and including a featureless region disposed within the first pattern such that the planar <a href="lightwave">lightwave</a> circuit is incomplete, the slave mask including a second

pattern having features for completing the planar lightwave

circuit;

(b) using the photolithographic mask set to expose at

least part of a substrate;

(c) processing the exposed substrate to fabricate the

planar <u>lightwave</u> circuit;

(d) analyzing the fabricated planar lightwave circuit;

and

(e) determining an optimized planar <u>lightwave</u> circuit in

dependence upon the analysis.

4

FONDEUR ET AL

Serial No. 10/736,295

Filed: **12/15/2003** 

10. (withdrawn-currently amended) A method according to claim

9, comprising the step of fabricating the optimized planar lightwave circuit.

11. (withdrawn) A method according to claim 9, wherein step

(b) comprises:

aligning the master mask above the substrate and exposing the substrate through the master mask; and,

aligning the slave mask above the substrate and exposing the substrate through the slave mask, the slave mask aligned such that features in the second pattern align with corresponding features in the first pattern on the substrate.

- 12. (withdrawn-currently amended) A method according to claim 9, wherein the planar circuit is a planar lightwave circuit, and wherein step (d) comprises measuring at least one of phase and amplitude errors of the fabricated planar lightwave circuit.
- 13. (withdrawn) A method according to claim 12, wherein step (d) further comprises using the at least one measured error to

design at least one correcting slave mask.

- 14. (withdrawn) A method according to claim 13, wherein step
- (d) further comprises repeating steps (b) though (d) for the at least one correcting slave mask.
- 15. (withdrawn-currently amended) A method according to claim 9, wherein step (e) comprises calculating a desired modification to the slave mask to modify a property of the planar lightwave circuit.

FONDEUR ET AL

Serial No. 10/736,295 Filed: 12/15/2003

16. (withdrawn) A method according to claim 9, wherein step (b) comprises stitching the slave mask to the master mask

about a periphery of the featureless region.

17. (withdrawn) A method according to claim 13, comprising the step of writing a production mask from data from the master mask and the at least one correcting slave mask.

18. (withdrawn) A method according to claim 9, wherein step

(b) comprises the step of exposing a resist layer formed on an optical core layer.

19. (withdrawn-currently amended) A planar <u>lightwave</u> circuit fabricated from a photolithographic mask set comprising:

a substrate;

a first pattern formed on a layer of the substrate, the first pattern including features for forming part of a planar lightwave circuit; and

a second pattern formed on the layer of the substrate, the second pattern disposed within the first pattern and including features for completing the planar <u>lightwave</u> circuit,

wherein the second pattern includes at least one modificator section selected for optimizing the planar <a href="lightwave\_circuit.">lightwave\_circuit.</a>

20. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim 19, wherein the at least one modificator section is designed for compensating systematic errors produced by the first pattern.

FONDEUR ET AL

Serial No. **10/736,295** 

Filed: 12/15/2003

21. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim 19, wherein the at least one modificator section is designed for tuning the planar lightwave circuit. the planar circuit comprises a planar lightwave circuit.

- 22. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim <u>19</u> <u>21</u>, wherein the at least one modificator section includes a plurality of waveguides that are modified relative to a corresponding plurality of waveguides outside the modificator section.
- 23. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim 22, wherein the modifications comprise at least one expanded width of a waveguide.
- 24. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim 22, wherein the modifications comprise at least one gap within a waveguide.
- 25. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim 22, wherein the modifications comprise at least one lateral offset between a section of a waveguide within the modificator section and a section of the waveguide outside the modificator section.
- 26. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim 22, wherein the modifications comprise at least one of an expanded waveguide width of a waveguide, a gap within a waveguide and a lateral offset between a section of a waveguide within the modificator section and a section of the waveguide outside the modificator section.
- 27. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim 1921, wherein the at least one modificator

FONDEUR ET AL

Serial No. 10/736,295

Filed: 12/15/2003

section is designed for changing an optical response of the planar lightwave circuit that is substantially determined by the first pattern.

- 28. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim  $\underline{2621}$ , wherein the at least one modificator section is designed for compensating systematic errors produced by the first pattern.
- 29. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim 21, wherein the planar lightwave circuit comprises an arrayed waveguide grating having a plurality of waveguides of different lengths arranged in an arc on the substrate.
- 30. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim 29, wherein the at least one modificator section substantially bisects the arc.
- 31. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim 30, wherein the at least one modificator section is a rectangular straight region.
- 32. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim 30, wherein the at least one modificator section includes an elliptical region.
- 33. (withdrawn-currently amended) A planar <u>lightwave</u> circuit according to claim <u>1921</u>, wherein the at least one modificator section is designed for compensating variations in refractive index across the substrate.

FONDEUR ET AL

Serial No. 10/736,295 Filed: 12/15/2003

34. (withdrawn) A planar lightwave circuit comprising:

- a substrate;
- a plurality of waveguides arranged on the substrate; and
- a distinct region on the substrate wherein at least a portion of the plurality of waveguides therein are modified relative to the plurality of waveguides outside the distinct region, the modifications including at least one of an expanded waveguide width of a waveguide, a gap within a waveguide and a lateral offset between a section of a waveguide within the distinct region and a section of the waveguide outside the distinct region.
- 35. (withdrawn-currently amended) A method of fabricating a planar circuit utilizing the photolithographic mask set defined in claim 1, the method comprising:
  - (a) providing the photolithographic mask set;
- (b) using the photolithographic mask set to expose at least part of a substrate;
- (c) processing the exposed substrate to fabricate the planar <u>lightwave</u> circuit;
- (d) analyzing the fabricated planar <u>lightwave</u> circuit; and
- (e) determining an optimized planar <u>lightwave</u> circuit in dependence upon the analysis.
- 36. (new) A photolithographic mask set according to claim 1, wherein the first pattern is for providing a general layout of

In re Patent Application of:
FONDEUR ET AL
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the planar lightwave circuit, and wherein the features in the second pattern are for tuning the planar lightwave circuit.